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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/971,711	10/09/2001	Satoshi Sugaya	Q66406	4242
7590 10/28/2004			EXAMINER	
SUGHRUE, MION, ZINN, MACPEAK & SEAS, PLLC			JACKSON, ANDRE K	
Suite 800			ART UNIT	PAPER NUMBER
2100 Pennsylvania Avenue, N.W. Washington, DC 20037-3213				THI DICTIONIDDIC
Washington, L	OC 20037-3213		2856	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s) SUGAYA ET AL.	
Advisory Action	09/971,711		
Advisory Action	Examiner	Art Unit	,
	André K. Jackson	2856	And
The MAILING DATE of this communica	ntion appears on the cover sheet with	th the correspondence ad	dress
THE REPLY FILED 06 October 2004 FAILS TO Therefore, further action by the applicant is required in rejection under 37 CFR 1.113 may only be condition for allowance; (2) a timely filed Notice Examination (RCE) in compliance with 37 CFR	uired to avoid abandonment of this either: (1) a timely filed amendmer of Appeal (with appeal fee); or (3)	application. A proper rep nt which places the applic	ly to a ation in
PERIOD	FOR REPLY [check either a) or b)]	
a) The period for reply expires <u>3</u> months from the		and finally to the final actualism on	bisha asia latan da
b) The period for reply expires on: (1) the mailing d no event, however, will the statutory period for re ONLY CHECK THIS BOX WHEN THE FIRST R 706.07(f).	eply expire later than SIX MONTHS from th	e mailing date of the final rejec	tion.
Extensions of time may be obtained under 37 CFR 1.1 fee have been filed is the date for purposes of determining fee under 37 CFR 1.17(a) is calculated from: (1) the expiral (2) as set forth in (b) above, if checked. Any reply received timely filed, may reduce any earned patent term adjustmen	the period of extension and the correspond tion date of the shortened statutory period f by the Office later than three months after	ling amount of the fee. The appoint of the final time in the final time.	oropriate extension II Office action; or
1. A Notice of Appeal was filed on A 37 CFR 1.192(a), or any extension thereo			
2. The proposed amendment(s) will not be e	entered because:		
(a) they raise new issues that would req	uire further consideration and/or se	earch (see NOTE below);	,
(b) they raise the issue of new matter (s	ee Note below);		
(c) they are not deemed to place the application issues for appeal; and/or	plication in better form for appeal b	y materially reducing or s	implifying the
(d) they present additional claims without	ut canceling a corresponding numb	per of finally rejected clain	ns.
NOTE: See Continuation Sheet.			
3. Applicant's reply has overcome the follow	ving rejection(s):	•	
 Newly proposed or amended claim(s) canceling the non-allowable claim(s). 	would be allowable if submitted	l in a separate, timely filed	d amendment
5. The a) affidavit, b) exhibit, or c) reapplication in condition for allowance because		n considered but does NO	OT place the
6. The affidavit or exhibit will NOT be consideral raised by the Examiner in the final rejection.		LELY to issues which we	re newly
7. For purposes of Appeal, the proposed an explanation of how the new or amended			and an
The status of the claim(s) is (or will be) as	s follows:		
Claim(s) allowed:	•		
Claim(s) objected to:			
Claim(s) rejected: <u>14-21</u> .			
Claim(s) withdrawn from consideration:	· .		
8. The drawing correction filed on is:		red by the Examiner.	

10. Other: ____

9. Note the attached Information Disclosure Statement(s)(PTO-1449) Paper No(s). _____.

Continuation of 2. NOTE: Applicants have argued that the Examiner's motivation to combine the Li et al. reference and Bennewitz et al. reference is not mentioned, taught and let alone suggested in the Li et al. reference and the Examiner has improperly borrowed from the Applicants' specification. Li et al. are concerned with making pyrochlore-type tungsten trioxide based sensors shown in figures 6 and 7 in as one embodiment of the invention. Applicants are strongly urged to see column 3 lines 25-65 of the Li et al. reference which provides the motivation to combine and since the duplication made here may not be accurate, column 3 lines 25-65 of the Li et al.: "During this heating process, the pyrochlore-type crystalline structure of tungsten trioxide would have been destroyed, thus rendering it impossible for use as a sensing element in a humidity sensor. The primary object of the present invention is to develop a solid-state humidity sensor, which contains pyrochlore-type tungsten trioxide in its sensing element. More specifically, the primary object of the present invention is to develop a hydrothermal process for making pyrochlore-type crystalline tungsten trioxide powders and/or growing pyrochlore-type crystalline tungsten trioxide films on a substrate, so as to enable a solid state humidity sensor to be made from pyrochlore-type tungsten trioxide. The pyrochlore-type tungsten trioxide based humidity sensors developed in the present invention exhibit excellent linearity between the resistance and relative humidity, and provide excellent ruggedness, durability, improved temperature and chemical resistances, as well as improved durability for long term use in high-humidity environments. The pyrochlore-type tungsten trioxide has a general formula of (M.sub.2 O).sub.x WO.sub.3 zH.sub.2 O, where M is a cation, x is approximately equal to 0.5, and z, which is the amount of crystalline water, is less than about 2. The value of z can vary depending on the water vapor pressure of the surroundings. In the process disclosed in the present invention, a tungstate salt (such as sodium tungstate, Na.sub.2 WO.sub.4.2H.sub.2 O) is first dissolved into a solution. Then, the pH of the tungstate salt solution is adjusted to acidic or slightly basic (pH less than 8.5). After heating in a pressured vessel at temperatures above 70.degree. C., pyrochlore-type tungsten trioxide is obtained. Depending on whether a powder is formed during the hydrothermal process (due to precipitation), and the construction of the sensing element, the pyrochlore-type tungsten trioxide based sensing elements can be prepared according to four basic embodiments. First, a pair of electrodes can be screen-printed on one surface of a ceramic insulating substrate, then a powdery pyrochlore-type tungsten trioxide is screen-printed over the electrodes. Second, after the pair of electrodes are screen-printed on the surface of a ceramic insulating substrate, a pyrochlore-type crystalline tungsten trioxide film can be caused to grow over the electrodes". Applicants have also argued that Li et al. do not describe the structure of having an upper electrode joined to both the moisture sensitive layer and the insulating substrate. In Column 6, lines 21-49 and figures 6 and 7 this arrangement is shown and discussed.

In response to Applicant's argument that neither Kampe et al. nor Mobius et al. relate to humidity sensors, a recitation of the intended use of the claimed invention must result in a structural difference between the claimed invention and the prior art in order to patentably distinguish the claimed invention from the prior art. If the prior art structure is capable of performing the intended use, then it meets the claim. In a claim drawn to a process of making, the intended use must result in a manipulative difference as compared to the prior art. See In re Casey, 152 USPQ 235 (CCPA 1967) and In re Otto, 136 USPQ 458, 459 (CCPA 1963). The structure of the claim does not mention anything about a humidity sensor. Applicants argue that the filter film in the Tanino et al. reference has nothing to do with the humidity sensing part. The claim calls for a moisture sensitive layer, which is provided by Tanino et al. as element (10). Applicants are correct it has nothing to do with the humidity sensing part. The claim does not state that the moisture sensitive layer provides a measurement of humidity. The claim only states that there is a moisture sensitive layer, which is provided by Tanino et al. as film (10).

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